Biography: Paul van der Heide

Paul is Director of MCA (Materials and Component Analysis) at imec, Leuven, Belgium. The scope of MCA is a) to support the characterization needs of the imec facilities (capabilities include APT, Raman, RBS, SIMS, SPM, TEM, XPS, etc.), and b) to explore, develop and implement the characterization capabilities required for tomorrow's industry.

Prior to moving to imec, Paul held positions at GLOBALFOUNDRIES, Malta, NY, USA (where he headed the end to end analytical labs support for high volume semiconductor device manufacturing and R&D), Samsung, Austin, TX, USA (where he established and managed the surface characterization labs for supporting high volume semiconductor device manufacturing), and the University of Houston, TX, USA (where he lectured courses in physical chemistry and surface analysis, while also managing the MRSEC SIMS-XPS facility).

Paul earned a PhD in Physical Chemistry from the University of Auckland, New Zealand (topic concerned the design and construction of a magnetic sector SIMS instrument), has authored over 100 publications in international peer reviewed journals, and is sole author of two books published through Wiley.